

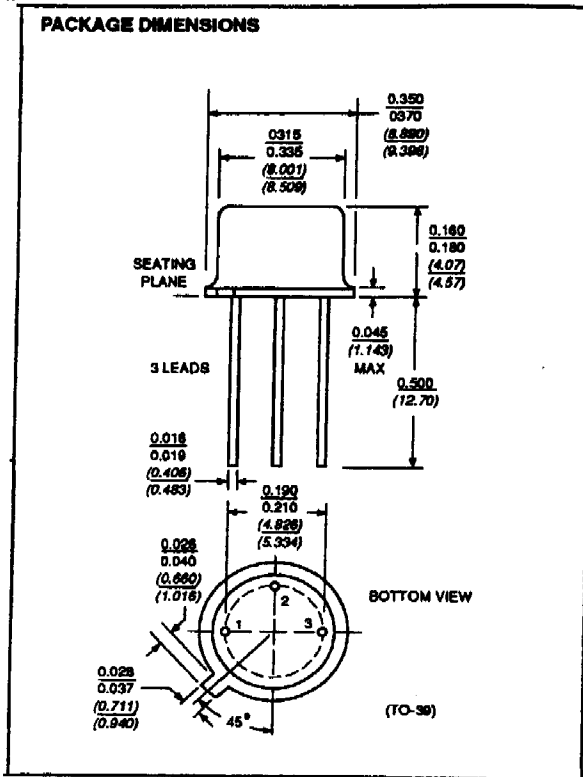
2N6794

**N-CHANNEL
 POWER MOSFET**

BV_{DSS} 500V
 $I_{D(cont)}$ 1.5
 $R_{DS(on)}$ 3.0 Ω

FEATURES

- AVALANCHE ENERGY RATED
- HERMETICALLY SEALED
- DYNAMIC dv/dt RATING
- SIMPLE DRIVE REQUIREMENTS



ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^{\circ}C$ unless otherwise stated)

V_{GS}	Gate - Source Voltage	$\pm 20V$
I_D	Continuous Drain Current ($V_{GS} = 10V, T_{case} = 25^{\circ}C$)	1.5A
I_D	Continuous Drain Current ($V_{GS} = 10V, T_{case} = 100^{\circ}C$)	1A
I_{DM}	Pulsed Drain Current ¹	6.5A
P_D	Power Dissipation @ $T_{case} = 25^{\circ}C$	20W
	Linear Derating Factor	0.16W/ $^{\circ}C$
E_{AS}	Single Pulse Avalanche Energy ²	0.11mJ
dv/dt	Peak Diode Recovery ³	3.5V/ns
T_J, T_{stg}	Operating and Storage Temperature Range	-55 to 150 $^{\circ}C$
$R_{\theta JC}$	Thermal Resistance Junction to Case	6.25 $^{\circ}C/W$
$R_{\theta JCA}$	Thermal Resistance Junction-to-Ambient	175 $^{\circ}C/W$

Notes

- 1) Pulse Test: Pulse Width $\leq 300\mu s$, $\delta \leq 2\%$
- 2) @ $V_{DD} = 50V, L \geq 0.100mH, R_G = 25\Omega$, Peak $I_L = 1.5A$, Starting $T_J = 25^{\circ}C$
- 3) @ $I_{SD} \leq 1.5A, di/dt \leq 50A/\mu s, V_{DD} \leq BV_{DSS}, T_J \leq 150^{\circ}C$, SUGGESTED $R_G = 7.5\Omega$



ELECTRICAL CHARACTERISTICS (T_{amb} = 25°C unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit	
STATIC ELECTRICAL RATINGS						
BV _{DSS}	Drain – Source Breakdown Voltage	V _{GS} = 0	I _D = 1mA	500	V	
ΔBV _{DSS}	Temperature Coefficient of Breakdown Voltage	Reference to 25°C		0.43	V/°C	
R _{DS(on)}	Static Drain – Source On–State Resistance	V _{GS} = 10V	I _D = 1A	3	Ω	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} = 10V	I _D = 1.5A	3.45	V	
g _{fs}	Forward Transconductance	V _{DS} = V _{GS}	I _D = 250μA	2	S(r)	
I _{DSS}	Zero Gate Voltage Drain Current	V _{GS} = 0	V _{DS} = 0.8BV _{DSS} T _J = 125°C	1	μA	
I _{GSS}	Forward Gate – Source Leakage	V _{GS} = 20V		25	nA	
I _{GSS}	Reverse Gate – Source Leakage	V _{GS} = -20V		100	nA	
DYNAMIC CHARACTERISTICS						
C _{iss}	Input Capacitance	V _{GS} = 0		350	pF	
C _{oss}	Output Capacitance	V _{DS} = 25V		80	pF	
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		35	pF	
Q _g	Total Gate Charge	V _{GS} = 10V	I _D = 1.5A	7.3	16.7	nC
Q _{gs}	Gate – Source Charge	V _{DS} = 0.5BV _{DS}		0.1	3	nC
Q _{gd}	Gate – Drain ("Miller") Charge	I _D = 1.5A		3.7	8.7	nC
t _{d(on)}	Turn–On Delay Time	V _{DS} = 0.5BV _{DS}			40	ns
t _r	Rise Time	V _{DD} = 250V			30	ns
t _{d(off)}	Turn–Off Delay Time	I _D = 1.5A			60	ns
t _f	Fall Time	R _G = 7.5Ω			30	ns
SOURCE – DRAIN DIODE CHARACTERISTICS						
I _S	Continuous Source Current			1.5	A	
I _{SM}	Pulse Source Current ²			6.5	A	
V _{SD}	Diode Forward Voltage	I _S = 1.5A	T _J = 25°C	1.2	V	
t _{rr}	Reverse Recovery Time	V _{GS} = 0		900	ns	
Q _{rr}	Reverse Recovery Charge	I _F = 1.5A	T _J = 25°C	5.9	μC	
t _{on}	Forward Turn–On Time	d _t / d _t ≤ 100A/μs	V _{DD} ≤ 50V	Negligible		
PACKAGE CHARACTERISTICS						
L _D	Internal Drain Inductance (from centre of drain pad to die)			5.0	nH	
L _S	Internal Source Inductance (from centre of source pad to end of source bond wire)			15.0	nH	

Notes

- 1) Pulse Test: Pulse Width ≤ 300μs, δ ≤ 2%
- 2) Repetitive Rating – Pulse width limited by maximum junction temperature.